Search Notes

Application/Control No.	Applicant(s)/Patent Unde Reexamination	
	KARR ET AL.	
Examiner	Art Unit	

2618

SEARCHED					
Class	Subclass	Date	Examiner		
455	550, 552.1, 553.1, 556.1, 557, 41.1, 41.2, 41.3, 515, 102, 108, 110, 115.1, 115.3, 161.1, 161.3, 226.2, 205, 208, 334	2/26/06	DN		
Updated	same as aboves	10/20/06	DN		

DUC M NGUYEN

SEARCH NOTES			
Search Notes	Date	Examiner	
see EAST earch history	7/2/07	DN	
	3/4/08	DN	

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

/DUC M NGUYEN/ Primary Examiner.Art Unit 2618

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